

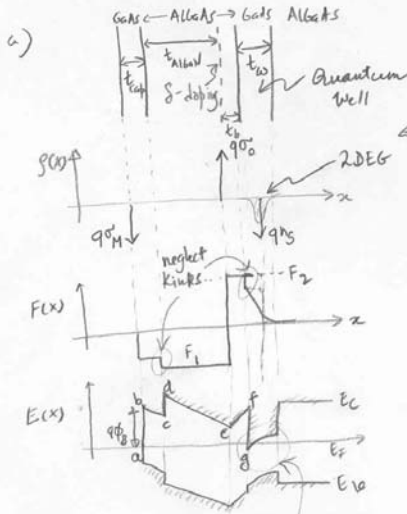


PROBLEM 2 HEMT design

(2)

We need  $n_s = 10^{12}/\text{cm}^2$ , what's the reqd. sheet doping?

Assume sheet doping =  $q\sigma_0$   $\text{Coul}/\text{cm}^2$



Charge conservation:  $q\sigma_M + qn_s = q\sigma_0$

Go around the loop in the band diagram

$$E_f \rightarrow a \rightarrow b \rightarrow c \rightarrow d \rightarrow e \rightarrow f \rightarrow g \rightarrow E_f$$

$$+ \underbrace{\frac{q\sigma_M}{\epsilon_s}}_{\uparrow} - F_1 + t_{cap} + \Delta E_c + \underbrace{\frac{qn_s}{\epsilon_s}}_{\uparrow} - F_2 + t_b - \Delta E_c + (E_0 - E_2) + (E_f - E_0) = 0$$

(a)  $E_0 - E_c =$  Ground-state of a Q-well.

assume  $\infty$ -well  $\approx 25\text{meV}$  (See pg 33 of NOTES)

$t_w = 15\text{nm}$   
Can assume  $\Delta$  well too...

also,  $q\sigma_M = q(\sigma_0 - n_s)$

$\frac{\partial D D S}{\partial x} = \frac{m^*}{\pi \hbar^2}$   
 $(E_f - E_0) + \frac{\pi \hbar^2 n_s}{m^*} \approx n_s$   
 $\therefore (E_f - E_0) \approx \frac{\pi \hbar^2 n_s}{m^*}$

$\Rightarrow$

$$q\sigma_0 - \frac{q(\sigma_0 - n_s)}{\epsilon_s} (t_{cap} + t_{AlGaAs}) + \frac{qn_s}{\epsilon_s} t_b + \frac{(E_0 - E_c)}{q} + \frac{(E_f - E_0)}{q} = 0$$

effective Bohr radius

$$\Rightarrow \sigma_0 \approx \frac{\epsilon_s}{q(t_{cap} + t_{AlGaAs})} \left[ \frac{\phi_B + E_0 - E_c}{q} \right] + n_s \left\{ 1 + \frac{t_b + \pi \frac{\hbar^2 \epsilon_s}{q m^*}}{t_{cap} + t_{AlGaAs}} \right\}$$

$$\approx 2.1 \times 10^{12} + 1.9 \times 10^{12}$$

$\sigma_0 \approx 4 \times 10^{12}/\text{cm}^2$

Note: This is a crude estimate. If you assume a  $\Delta$ -Quantum well, you'll get

$\sigma_0 \approx 3.3 \times 10^{12}/\text{cm}^2$

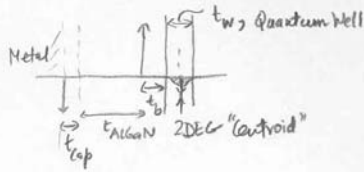
The method is more important here.

Prob 2: Guided...



(b)

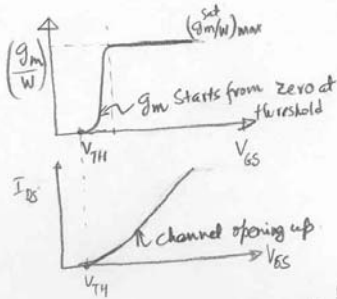
$$\left(\frac{g_{m, \text{Set}}}{W}\right)_{\text{max}} = C_g v_{\text{Sat}} \approx \left(\frac{\epsilon_s}{t_{M \rightarrow 2\text{DEG}}}\right) * (v_{\text{Sat}}) \leftarrow \text{Short-channel transconductance...}$$



$$t_{M \rightarrow 2\text{DEG}} = t_{\text{cap}} + t_{\text{AlGaN}} + t_b + t_{w/2} \quad \text{approximate}$$

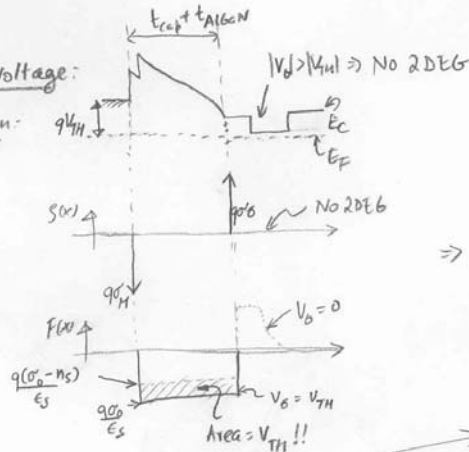
$$\left(\frac{g_{m, \text{Set}}}{W}\right)_{\text{max}} \approx \frac{13 * 8.85 * 10^{-14} * 10^7}{(5 + 30 + 2 + 7.5) * 10^{-7}} \frac{\text{S}}{\text{cm}} = 2.58 \text{ S/cm} = 258 \text{ S/m}$$

$$\left(\frac{g_{m, \text{Set}}}{W}\right)_{\text{max}} \approx 258 \text{ mS/mm} \quad \text{Constant at saturation region.}$$



Threshold Voltage:

Approximate solution:



$$\Rightarrow |V_{TH}| = \left[ \frac{q n_0'}{\epsilon_s} - \frac{q (n_0' - n_s)}{\epsilon_s} \right] * (t_{\text{cap}} + t_{\text{AlGaN}})$$

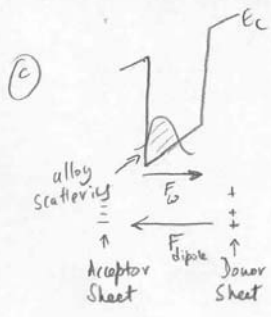
$$= \frac{q n_s}{\epsilon_s} * (t_{\text{cap}} + t_{\text{AlGaN}})$$

$$= 0.48 \text{ volts.}$$

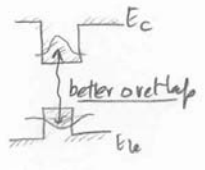
Note:

$$|V_{TH}| = \frac{q n_s * 2\text{DEG charge}}{\epsilon_s / (t_{\text{cap}} + t_{\text{AlGaN}})} \quad \therefore V_{TH} \approx 0.48 \text{ Volt}$$

$$\left[ \frac{\epsilon_s}{t_{\text{cap}} + t_{\text{AlGaN}}} \right] \leftarrow \text{capacitance}$$



One can dope an "inverse" sheet dipole to cancel the electric field in the well. It needs an equal & opposite donor-acceptor sheet (or  $\delta^-$ ) doping as shown.



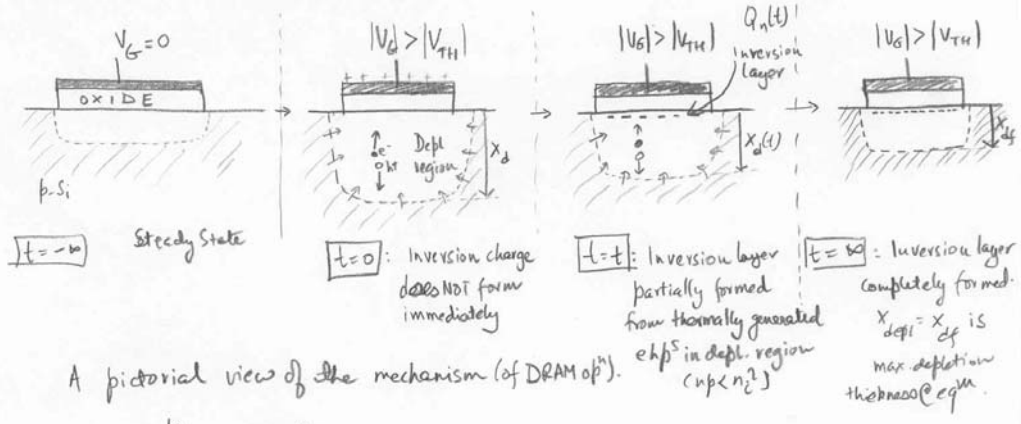
If there is an electric field in a QWell, & you want to use it for an optical device, the electron & holes are pushed in opposite directions & the chances

of them recombining & giving out photons is reduced. This is called the Quantum-Confined Stark Effect (QCSE). So for good optical devices, it is highly desirable to have flat wells so that e-h overlap is high. If I flatten the well for the HEMT though with doping, ionized impurity scattering will increase, & chances are that mobility will go down. However, alloy scattering, which occurs due to penetration of 2DEG wave<sup>n</sup> into the barrier is reduced, since the 2DEG is pushed away from the surface... It's always give and take 😊

PROBLEM 3

MOS Capacitor

(5)



A pictorial view of the mechanism (of DRAM op<sup>n</sup>).

$$\frac{dQ_n}{dt} = -\frac{q n_i (x_d - x_{df})}{\tau C_{ox}} \rightarrow \text{use this, \& simple charge conservation}$$

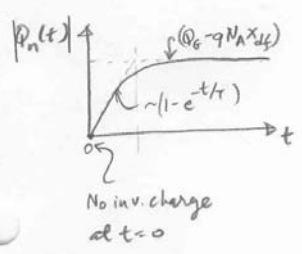
$$Q_n(t) + q N_A x_d(t) = |Q_G|$$

↑  
in  
eliminate  $x_d(t)$

(a)  $Q_n + \underbrace{\left(\frac{2\epsilon_0 N_A}{n_i}\right)}_T \frac{dQ_n}{dt} = -[Q_G - q N_A x_{df}]$

(b) Solve:  $\int_{Q_n(0)=0}^{Q_n(t)} \frac{dQ_n}{(Q_n + Q_G - q N_A x_{df})} = -\int_0^t \frac{dt}{T}$

$$\ln\left(\frac{Q_n(t) + Q_G - q N_A x_{df}}{Q_G - q N_A x_{df}}\right) = -t/T$$



$$\Rightarrow Q_n(t) = -(Q_G - q N_A x_{df}) (1 - e^{-t/T})$$

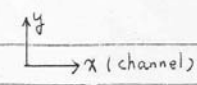
$$T = \frac{2\epsilon_0 N_A}{n_i} = (2 \times 10^{-6} s) \times \left(\frac{10^{15} / \text{cm}^3}{10^{10} / \text{cm}^3}\right) \approx 0.2 \text{ seconds}$$

Since the time req<sup>d</sup> to form the layer is in the order of seconds, one can come back to the MOS capacitor after many clock cycles & find what had been stored there before  $\Rightarrow$  it is a memory...

PROBLEM 4 (Soln. by Qin Zhang, my comments...)

5

P4. a)



$$J_{\text{drift}}(x, y) = q \mu_n n(x, y) * F_x$$

$$I_{\text{drift}}(x) = \int_0^{y_i} J_{\text{diff}}(x, y) z dy$$

$$\int n(x, y) dy = \int n(\psi) d\psi$$

in linear  $F_x \approx V_{DS}/L = \frac{q \mu_n V_{DS} z}{L} \int_0^{y_i} n(x, y) dy = \int n(\psi) d\psi$  (related to field)

strong inversion  $= \frac{q \mu_n V_{DS} z}{L} \int_{\psi_0}^{\psi_s} n_{po} e^{\frac{q(\psi - V(x))}{kT}} d\psi$

$$I_{\text{drift}}(x) = \frac{q \mu_n V_{DS} z n_{po} L_0}{\sqrt{2} k T L} \int_{\psi_0}^{\psi_s} \frac{e^{\frac{q}{kT}(\psi - V(x))}}{F(\frac{q\psi}{kT}, V(x), n_{po}/p_{po})} d\psi$$

where  $V(x) \approx \frac{V_{DS}}{L} x$ .

$$F(\frac{q\psi}{kT}, V(x), n_{po}/p_{po}) = \left[ e^{-\frac{q\psi}{kT}} + \frac{q\psi}{kT} - 1 + \frac{n_{po}}{p_{po}} e^{-\frac{qV(x)}{kT}} \left( e^{\frac{q\psi}{kT}} - \frac{q\psi}{kT} e^{\frac{qV(x)}{kT}} - 1 \right) \right]^{1/2}$$

$$J_{\text{diff}}(x, y) = q D_n \nabla n$$

$$I_{\text{diff}}(x) = \int_0^{y_i} z q D_n \frac{dn(x, y)}{dx} dy$$

$$= \frac{d}{dx} \int_0^{y_i} z q D_n n(x, y) dy$$

$$= q D_n z \frac{d}{dx} \int_{\psi_0}^{\psi_s} \frac{n_{po} e^{\frac{q(\psi - V(x))}{kT}}}{(\sqrt{2} k T / q L_0) F(\frac{q\psi}{kT}, V(x), n_{po}/p_{po})} d\psi$$

$$I_{\text{diff}}(x) = \frac{q \mu_n z n_{po} L_0}{\sqrt{2}} \frac{d}{dx} \int_{\psi_0}^{\psi_s} \frac{e^{\frac{q}{kT}(\psi - V(x))}}{F(\frac{q\psi}{kT}, V(x), n_{po}/p_{po})} d\psi$$

b)  $J_{\text{drift}}$  dominates

( $V_{DS}$  is small,  $\frac{dn}{dx}$  is small)